

**Search Notes**

Application/Control No.

10/649,625

Examiner

Jim Vannucci

Applicant(s)/Patent under  
Reexamination

SEKI, YUICHI

Art Unit

2828

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
same as above		2/21/2006	JV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
372/43, 372/50, identical, wafer lot	2/21/2006	JV